



Patent No. NEC00P063-TOb

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

Kazuki Yokota

Serial No.: 09/627,456

Group Art Unit: 2851

Filed: July 27, 2000

Examiner: Magda Cruz

For: OVERLAY MARK, METHOD OF MEASURING OVERLAY ACCURACY,
METHOD OF MAKING ALIGNMENT AND SEMICONDUCTOR DEVICE
THEREWITH

Honorable Commissioner of Patents
Alexandria, Virginia 22313-1450

**SUBMISSION OF VERIFIED ENGLISH TRANSLATION
OF THE PRIORITY DOCUMENT**

Sir:

Submitted herewith is a copy of the verified English translation of the Specification, Claims and Abstract, and the Declaration of Tomoyuki Okazawa, dated January 26, 2004, that the English translation is a true English translation of the Japanese Application Number 1999-213720 filed July 28, 1999, upon which application the claim for priority is based.

Approval and acknowledgment of receipt are respectfully requested.

Respectfully submitted,

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Date: 1/29/04

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